

N-channel 650 V, 0.75 Ω typ., 10 A Zener-protected SuperMESH3™ Power MOSFET in a TO-220FP narrow leads package

Datasheet – preliminary data

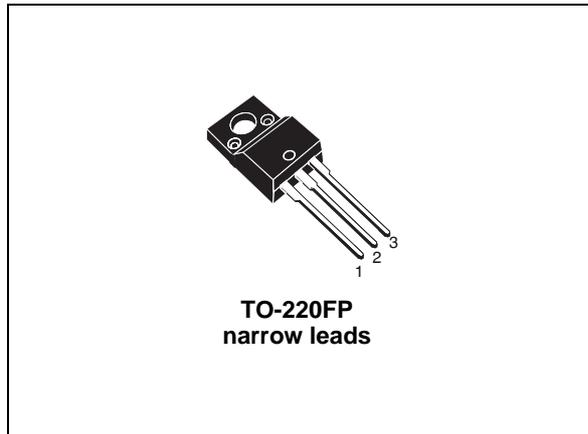
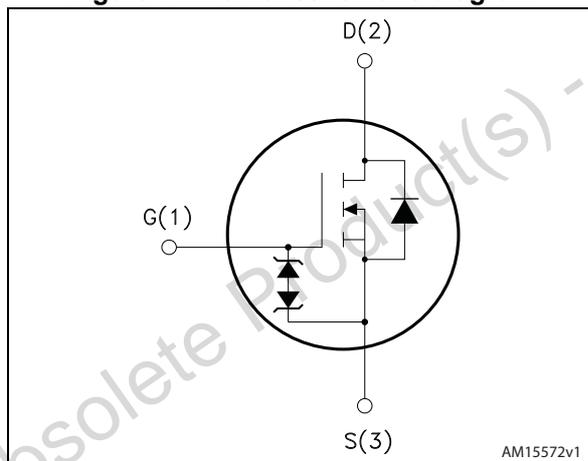


Figure 1. Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on) max}	I _D	P _{TOT}
STF10N65K3(045Y)	650 V	1 Ω	10 A	35 W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Very low intrinsic capacitance
- Improved diode reverse recovery characteristics
- Zener-protected

Applications

- Switching applications

Description

This SuperMESH3™ Power MOSFET is the result of improvements applied to STMicroelectronics' SuperMESH™ technology, combined with a new optimized vertical structure. This device boasts an extremely low on-resistance, superior dynamic performance and high avalanche capability, rendering it suitable for the most demanding applications.

Table 1. Device summary

Order code	Marking	Package	Packaging
STF10N65K3(045Y)	10N65K3	TO-220FP narrow leads	Tube

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Obsolete Product(s) - Obsolete Product(s)

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain source voltage	650	V
V_{GS}	Gate-source voltage	± 30	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$	10	A
I_D	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	6.3	A
$I_{DM}^{(1)}$	Drain current (pulsed)	40	A
P_{TOT}	Total dissipation at $T_C = 25\text{ }^\circ\text{C}$	35	W
I_{AR}	Max current during repetitive or single pulse avalanche (pulse width limited by T_{JMAX})	7.2	A
E_{AS}	Single pulse avalanche energy ⁽²⁾	212	mJ
	Derating factor	0.28	W/ $^\circ\text{C}$
dv/dt ⁽³⁾	Peak diode recovery voltage slope	12	V/ns
ESD	Gate-source human body model (R = 1.5 k Ω , C = 100 pF)	2.8	kV
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s; $T_C=25\text{ }^\circ\text{C}$)	2500	V
T_j	Operating junction temperature	-55 to 150	$^\circ\text{C}$
T_{stg}	Storage temperature		$^\circ\text{C}$

1. Pulse width limited by safe operating area.
2. Starting $T_j = 25\text{ }^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$
3. $I_{SD} \leq 10\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{Peak} < V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	3.57	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	$^\circ\text{C}/\text{W}$

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	650			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 650 V V _{DS} = 650 V, T _C =125 °C			1 50	μA μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			±10	μA
V _{GS(th)}	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 100 μA	3		4.5	V
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 3.6 A		0.75	1	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C _{iss}	Input capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0	-	1180	-	pF
C _{oss}	Output capacitance		-	125	-	pF
C _{riss}	Reverse transfer capacitance		-	14	-	pF
C _{oss eq.}	Equivalent output capacitance	V _{DS} = 0 to 520 V, V _{GS} = 0	-	77	-	pF
R _G	Intrinsic gate resistance	f=1 MHz open drain	-	3	-	Ω
Q _g	Total gate charge	V _{DD} = 520 V, I _D = 7.2 A, V _{GS} = 10 V (see Figure 16)	-	42	-	nC
Q _{gs}	Gate-source charge		-	7.4	-	nC
Q _{gd}	Gate-drain charge		-	23	-	nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 310 \text{ V}$, $I_D = 3.5 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see Figure 15)	-	14.5	-	ns
t_r	Rise time		-	14	-	ns
$t_{d(off)}$	Turn-off-delay time		-	44	-	ns
t_f	Fall time		-	35	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		7.2	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		28.8	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 7 \text{ A}$, $V_{GS} = 0$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 7 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see Figure 20)	-	320		ns
Q_{rr}	Reverse recovery charge		-	2		μC
I_{RRM}	Reverse recovery current		-	13		A
t_{rr}	Reverse recovery time	$I_{SD} = 7 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see Figure 20)	-	410		ns
Q_{rr}	Reverse recovery charge		-	2.9		μC
I_{RRM}	Reverse recovery current		-	14		A

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = 300 μs , duty cycle 1.5%

Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}$, $I_D = 0$	30	-	-	V

The built-in back-to-back Zener diodes have been specifically designed to enhance not only the device's ESD capability, but also to make them capable of safely absorbing any voltage transients that may occasionally be applied from gate to source. In this respect, the Zener voltage is appropriate to achieve efficient and cost-effective protection of device integrity. The integrated Zener diodes thus eliminate the need for external components.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

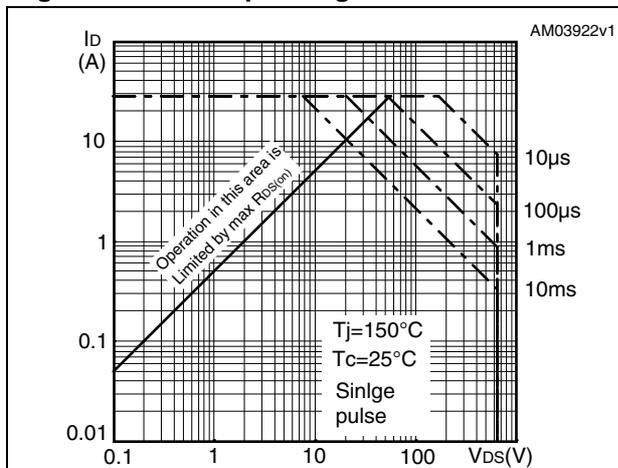


Figure 3. Thermal impedance

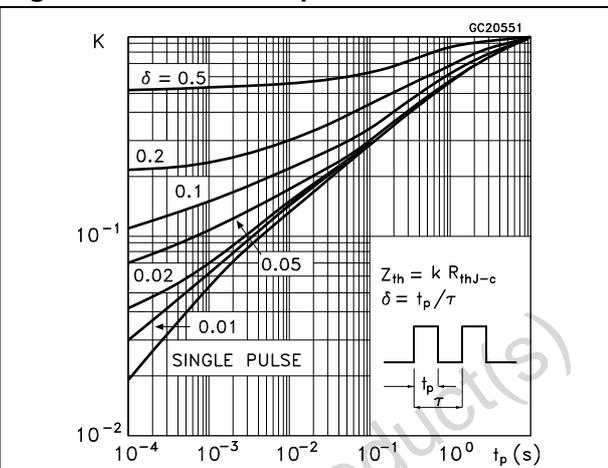


Figure 4. Output characteristics

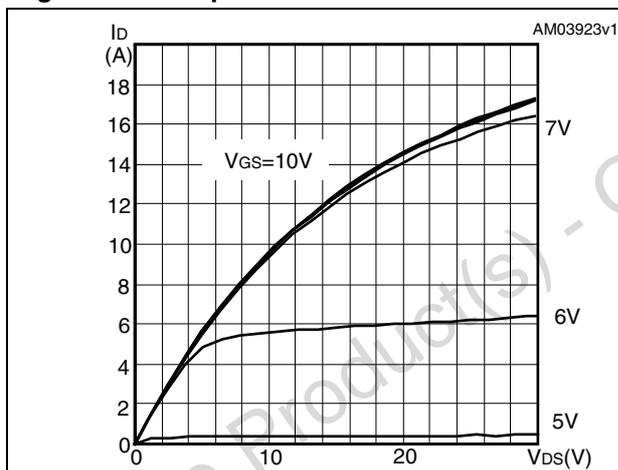


Figure 5. Transfer characteristics

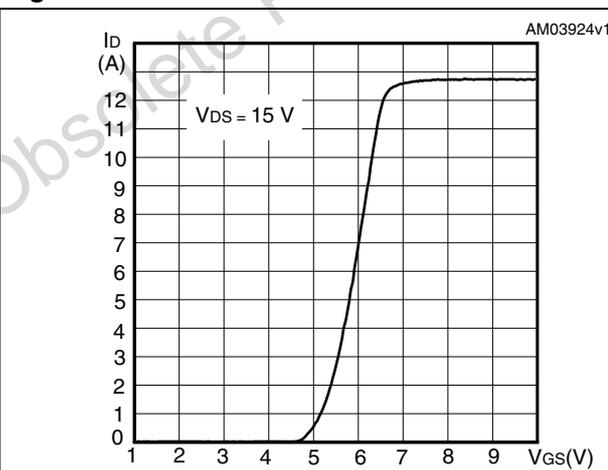


Figure 6. Normalized BV_{DSS} vs temperature

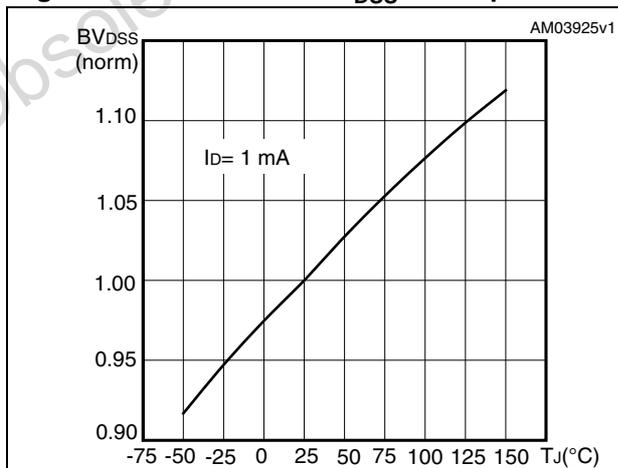


Figure 7. Static drain-source on resistance

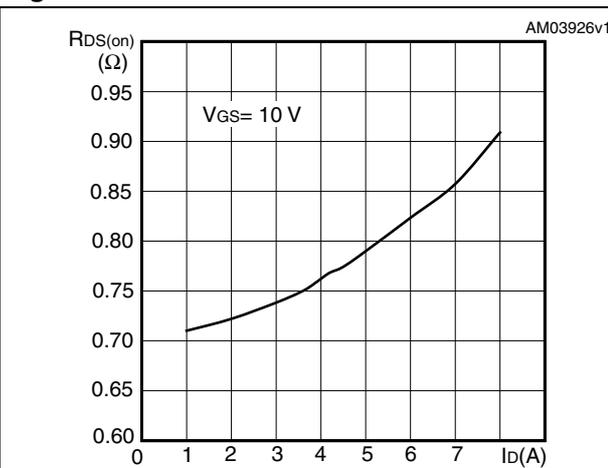


Figure 8. Output capacitance stored energy

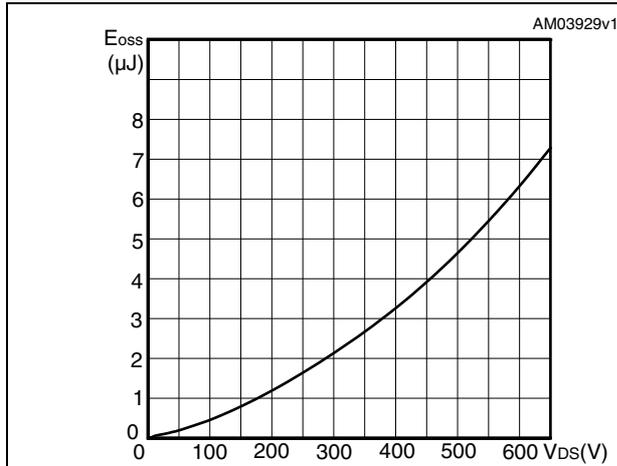


Figure 9. Capacitance variations

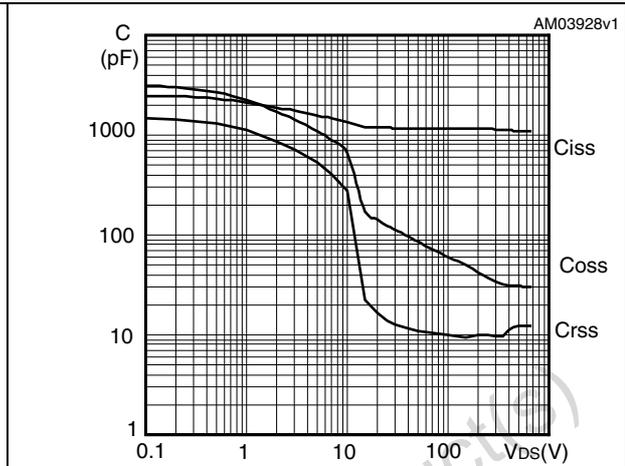


Figure 10. Gate charge vs gate-source voltage

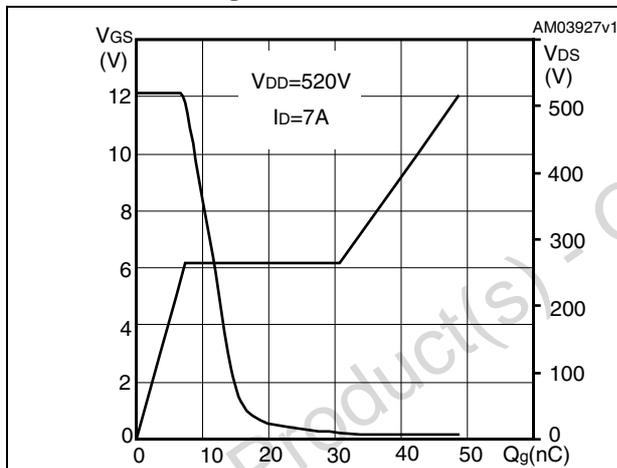


Figure 11. Normalized on-resistance vs temperature

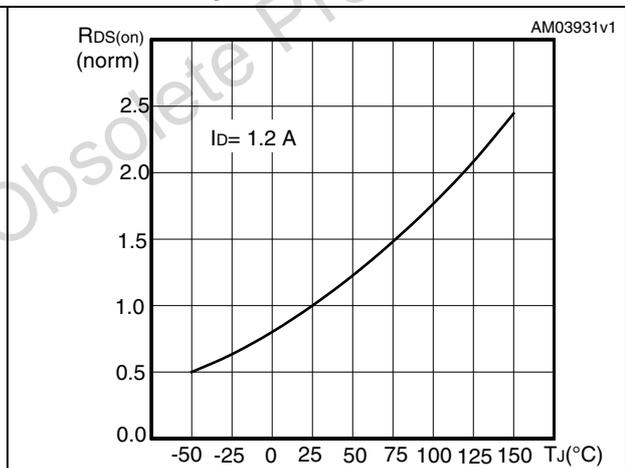


Figure 12. Normalized gate threshold voltage vs temperature

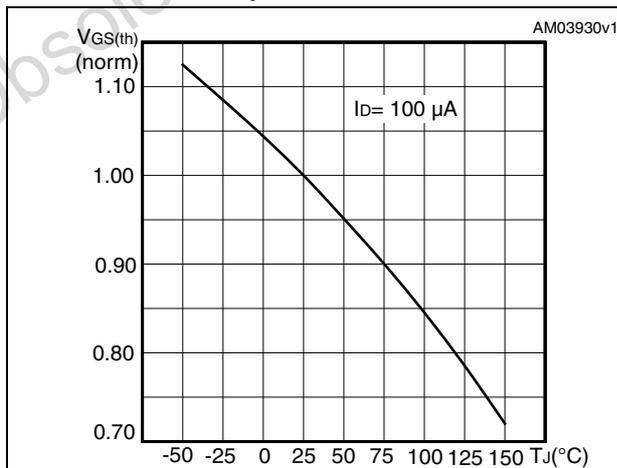


Figure 13. Maximum avalanche energy vs temperature

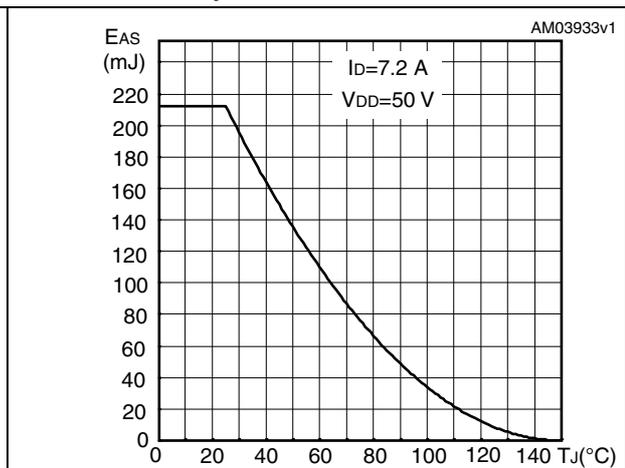
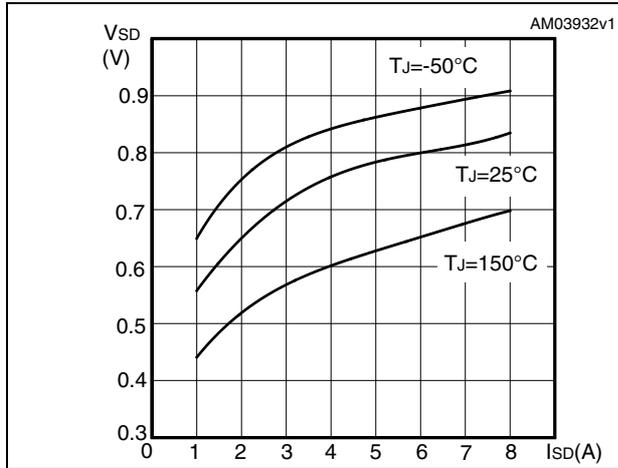


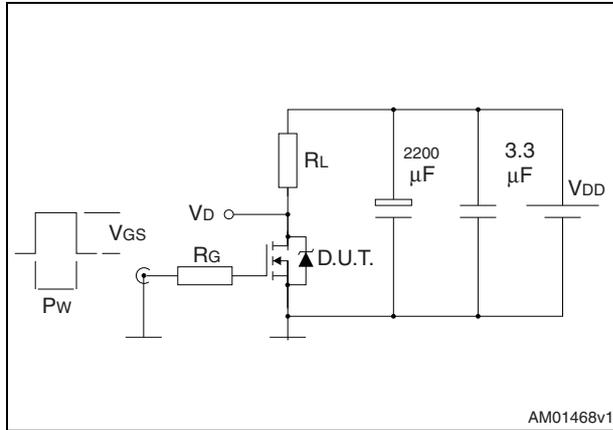
Figure 14. Source-drain diode forward characteristics



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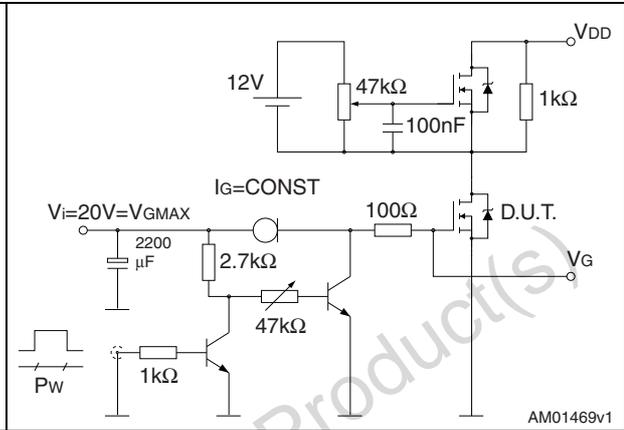
3 Test circuits

Figure 15. Switching times test circuit for resistive load



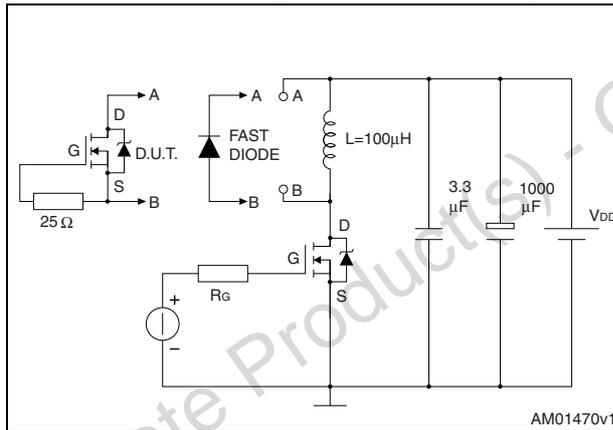
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Figure 16. Gate charge test circuit



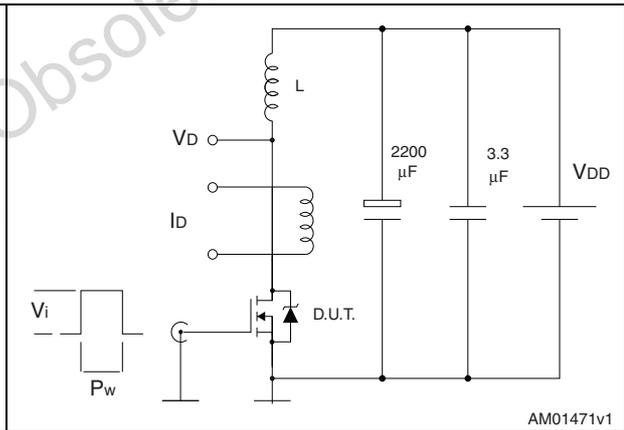
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Figure 17. Test circuit for inductive load switching and diode recovery times



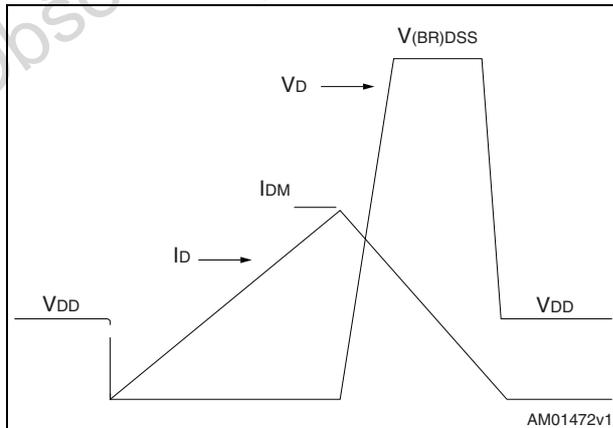
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Figure 18. Unclamped inductive load test circuit



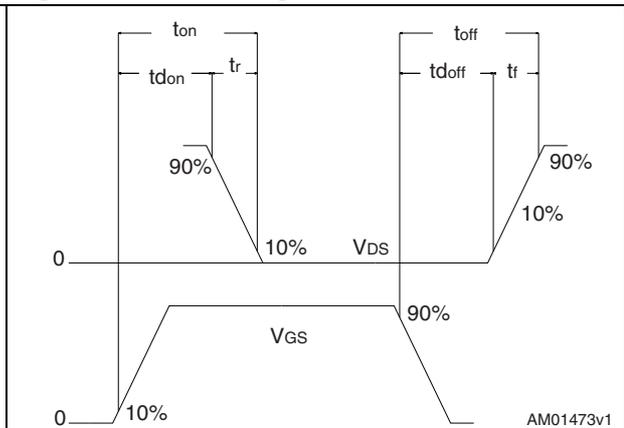
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Figure 19. Unclamped inductive waveform



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Figure 20. Switching time waveform



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4 Package mechanical data

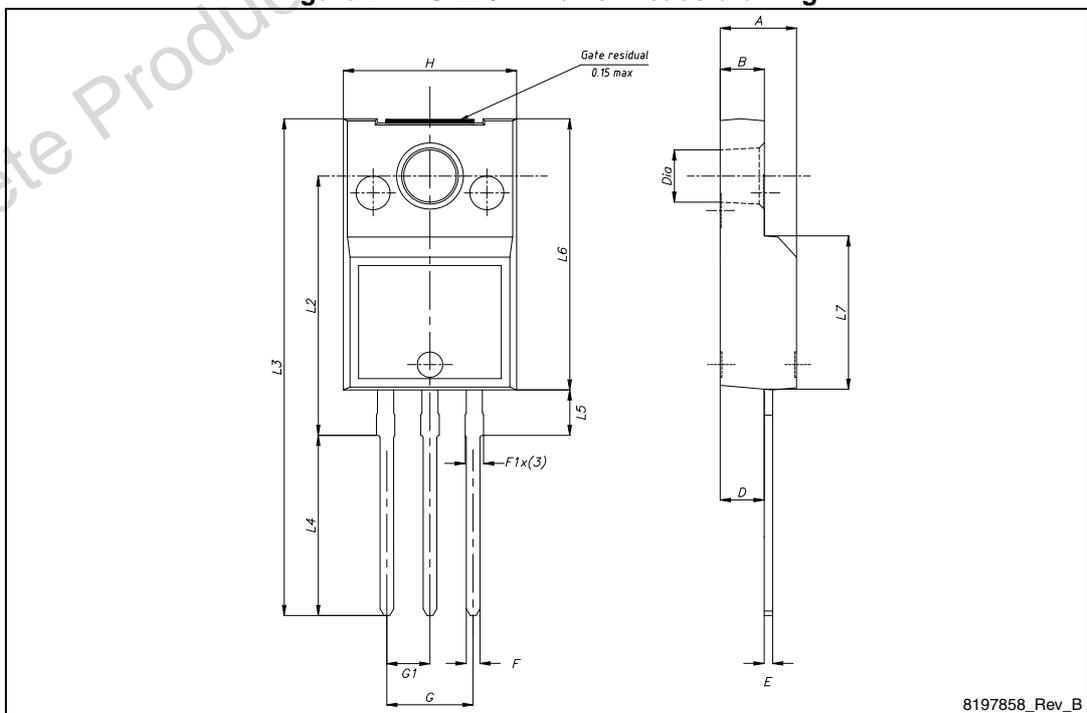
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Table 9. TO-220FP narrow leads mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	0.95		1.20
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2	15.20		15.60
L3	28.6		30.6
L4	10.3		11.1
L5	2.60	2.70	2.90
L6	15.8	16.0	16.2
L7	9		9.3
Dia	3		3.2

Figure 21. TO-220FP narrow leads drawing



8197858_Rev_B

5 Revision history

Table 10. Document revision history

Date	Revision	Changes
15-Apr-2013	1	First release.

Obsolete Product(s) - Obsolete Product(s)

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